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Modelling the broadband X-ray variability of black hole X-ray binaries

In the last 8 years, NICER and Insight-HXMT have opened up new windows to study X-ray variability from the softest to hardest X-rays. With a focus on insights from these instruments, I will review our current understanding of the origin of the rapid (minutes to milliseconds) X-ray variability in black hole X-ray binaries and how we can model the Fourier properties of the variability, to learn about the innermost regions and the disk-corona geometry.

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